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TITLE: Design of analog boundary scan circuits -

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PATENT-ASSIGNEE: NAT SCI COUNCIL[NASCN]

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PATENT-FAMILY:

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APPLICATION-DATA:

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ABSTRACTED-PUB-NO: TW 413981A

BASIC-ABSTRACT:

NOVELTY - Two new analog boundary scan designs for testing and diagnosing analog or mixed-mode circuits are invented. In this document the basic analog boundary scan cell, the defined instructions with the associated operations, and the control circuitry of each design are described. The advantages of these two designs include: (1) Signal at various test points can be sampled simultaneously, (2) test stimuli can be injected to various test points simultaneously and (3) test stimuli loading and test response outputting can be done simultaneously. The first design is for DC testing while the second design can be used for both DC and AC testing. However the control circuitry for the second design is more complex than that for the first design.

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CHOSEN-DRAWING: Dwg.1/1

TITLE-TERMS: DESIGN ANALOGUE BOUNDARY SCAN CIRCUIT

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